

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE  <b>LIST OF PRIOR ART CITED BY APPLICANT</b>  <i>(Use several sheets if necessary)</i>		<b>Atty. Docket No. (Optional)</b>  15608	<b>Application Number</b>  Unassigned  10/626,800			
		<b>Applicant(s)</b> Raul Curbelo				
		<b>Filing Date</b> Herewith	<b>Group Art Unit</b> Unassigned 2878			
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER INITIAL*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If appropriate)
OG	AA	4,682,022	7/21/87	Hoult et al.		
OG	AB	4,927,269	5/22/90	Keens et al.		
OG	AC	5,262,635	11/16/93	Curbelo		
	AD					
	AE					
<b>FOREIGN PATENT DOCUMENTS</b>						
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>						
OG		Schindler R.A., "Correcting for Nonlinearity in a Photodetector", <i>NASA Tech Briefs</i> 10(2), Item 52 (1986)				
OG		Zhang Z.M. et al., "Absolute Detector Calibration Applied to Nonlinearity Error Correction in FT-IR Measurements", <i>Applied Spectroscopy</i> 51(4):576-579 (1997)				
OG		Rahmelow K., "Electronic Influences on an Infrared Detector Signal: Nonlinearity and Amplification", <i>Applied Optics</i> 36(10):2123-2132 (1997)				
OG		Palchetti L. et al., "Assessment of Detector Nonlinearity in Fourier Transform Spectroscopy", <i>Applied Spectroscopy</i> 56(2):271-274 (2002)				
<b>EXAMINER</b>		<b>DATE CONSIDERED</b>				
OG Curbelo		06/18/04				
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						